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DATE: 13 MAY 2002' TIME SENT: 1:12 P.M.
TOTAL PAGES (INCLUDING COVER SHEET):
ATTENTION: M. ESTRADA
COMPANY NAME: U.S.P.T.O., ART UNIT # 2823
TO FAX NUMBER: (703) 308 - 7722 (7724, 3431, 3432)
TRANSMITTING FROM: ROSENBERG, KLEIN & LEE
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OUR DOCKET NO. <u>MR1035-8</u> 20 YOUR REFERENCE
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ADDITIONAL COMMENTS: AMENDMENT FOR ENTRY
<u> </u>

ROSENBERG KLEIN LEE

MR1035-820

CERTIFICATE OF FACSIMILE TRANSMISSION

I HEREBY CERTIFY that this Amendment responsive to the 13 February 2002 Office Action is being facsimile transmitted to Art Unit No. 2823 of the U.S. Patent and Trademark Office on the date shown below.

FOR: ROSENBERG, KLEIN & LEE

Registration No. 33,253

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FAX NO. 410 461 3067

Art Unit No. 2823

Examiner: M. Estrada

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MR1035-820

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Jeng et al.

Serial No.

File Date:

09/781,283

7761,265

02/13/2001

Title: Planarization Method Of Inter-Layer

Dielectrics And Inter-Metal Dielectrics

AMENDMENT

Box Non-fee Amendment Assistant Commissioner for Patents Washington, DC 20231 FAX COPY RECEIVED

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Sir;

In response to the First Office Action dated 13 February 2002, please enter the following Amendment.

IN THE CLAIMS:

Please replace the following Claims with the clean copies thereof, as follows:

Claim 1 should be replaced with:

1 (Once Amended) A planarization method of inter-layer dielectrics, comprising

the steps of: